

MECHANICAL ENGINEERING

Description of the search databases



Descriptions of the most frequently used databases.

Patent databases

Epodoc

The Epodoc database is the European Patent Organisation's own electronic patent database, containing classified patent applications/patents from 71 patent organisations. The database covers EP, PCT, OAPI and ARIPO completely, USA from 1832, England, France and Germany from app. 1920. Japan and other European countries are covered from 1971/74 to date. The database is updated weekly and the search is performed in the abstract of a patent/patent application filed by the applicant. In the case of older documents, searches can only be made on title and/or patent class/es. Searches cannot be made in the entire patent text. A citation search in Epodoc covers those documents cited in the subject patent application, as well as the documents cited by the technical examiner. The search also covers patent literature in which the subject document or its family is cited. The database PAJ from the Japanese Patent Organisation is included in this database.

WPI (World Patents Index)

The WPI database is made by the company Derwent and covers published patent applications and granted patents from more than 40 patent organisations. The database covers Belgium, Canada, France, Japan, the Netherlands, Germany, Russia / Soviet, South Africa, Switzerland, UK and USA from 1963, Czech Republic, Slovakia, Den-

mark, Finland, Israel, Hungary, Norway, Portugal, Romania, Austria and Sweden from 1974-75, PCT, EP, Italy and Brazil from 1976, Australia, Luxembourg and Spain from 1984, China and South Korea from 1987, New Zealand and Taiwan from 1993, Ireland and the Philippines from 1995, German utility models from 1996, and Mexico from 1998. The database covers the following subjects: pharmaceuticals from 1963, agricultural chemicals from 1965, plastics and polymers from 1966, all other chemicals from 1970, mechanics, electronics and all other technology in general from 1974. The database is updated weekly. The search is performed in the abstract of the patent/patent application. The abstract is formulated by the producer of the database. A search cannot be made in full patent text.

M-CAM

M-CAM is a database and a tool for retrieving and analysing patents. We have access to patent information from 84 countries. Companies which are citing or have cited a specific patent can be shown in a unique graphical manner. With this tool we can also retrieve patents which could have been cited or could be citing a specific patent using semantic searching. We are using M-CAM as a supplement to searches carried out in our other databases.

WIPSGLOBAL

This is a Korean database with English abstracts for Korean patent information back to 1979

for examined applications and back to 1983 for unexamined applications. We can find more patent information from Korea in this database than in possibly any other database in the world.

PAT-LIST-CN/WEB

This is a database covering Chinese patent information. Abstract and claim 1 is searchable in English language back to 1985.

Full-text search in TXTUS

This database covers the full text of all US-patent documents published since 1836. The entire patent text is searchable.

Full-text search in TXTEP

This database covers the full text of all EP-patent documents published since 1978. The entire patent text is searchable.

Full-text search in TXTWO

This database covers the full text of PCT applications published after 1970. The entire patent text is searchable.

Full-text search in TXTGB

This database covers the full text of GB-patent documents published since 1894. The entire patent text is searchable.

Full-text search in TXTAU

This database covers the full text of AU-patent documents published since 1967. The entire patent text is searchable.

Full-text search in TXTDE

This database covers the full text of DE-patent documents published since 1920. The entire patent text is searchable.



Full-text search in TXTAT

This database covers the full text of AT-patent documents published since 1902. The entire patent text is searchable.

Full-text search in TXTCH

This database covers the full text of CH-patent documents published since 1920. The entire patent text is searchable.

Full-text search in TXTFR

This database covers the full text of FR-patent documents published since 1920. The entire patent text is searchable.

Full-text search in TXTBE

This database covers the full text of BE-patent documents published since 1983. The entire patent text is searchable.

Full-text search in TXTCA

This database covers the full text of CA-patent documents published since 1981. The entire patent text is searchable.

Non-patent databases

COMPENDEX

The Computerized Engineering Index and Ei Engineering Meetings database (Ei COMPENDEX) contains citations from worldwide engineering and technology. COMPENDEX covers all engineering disciplines including chemical, computer, electrical, civil and mechanical engineering. Sources include journals, books, conference contributions, reports, and non-conventional literature. Bibliographic information and abstracts are searcha-

ble. File data from 1960 to present and the database is updated monthly.

INSPEC

The Information Service for Physics, Electronics and Computing database contains citations with abstracts to world physics, electronics and electrical engineering, computers and computing, and control theory and technology literature. INSPEC corresponds to physics abstracts, electrical & electronics abstracts, computer and control abstracts, and business automation. Sources for INSPEC include primarily journals, conference proceedings, books, dissertations and reports. Bibliographic information and abstracts are searchable. File data from 1898 and the database is updated weekly.

NPL

The NPL database contains the bibliographic data for Non-Patent Literature documents which have been cited in an EPO EP, WO or FR search report. The database is updated monthly. The sources are books, journals, technical reports, database citations, internet citations and conference proceedings. File data from 1989.

RDISCLOSURE

The Research Disclosure database contains the full text including images of technical disclosures of inventions published as an alternative to the patent system. Each record contains the title, a detailed description and illustrations of the invention, as well as a statement as to whether

the invention is disclosed anonymously or by company name. The database covers all areas of science and technology. The source is the monthly Journal Research Disclosure. File data from 1960 to the present and is updated monthly.

IEEE

The IEEE database contains documents produced by IEEE (Institution of Electrical and Electronic Engineers) in the fields of modern electronics including electronic science and engineering, telecommunications, optoelectronics and optical communication.

IOP

The IOP database contains citations within the technical areas: Biomedical materials, Physics, Engineering, Instrumentation, Microengineering, Optics, Nanotechnology, Nuclear Fusion and Conductors File data from 1899 to present.

AIP

In the AIP database full text articles from the American Institute of Physics are searchable back to 1995.

Further relevant databases available via Dialog or STN.

